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CALL FOR PAPERS

ATS'07

The Sixteenth Asian Test Symposium

October 9-11, 2007, Beijing Friendship Hotel, Beijing, P.R.China

Sponsored by

IEEE Computer Society
Test Technology Technical Council



IEEE



In cooperation with

Technical Committee on Fault Tolerant Computing
China Computer Federation



SCOPE

The Asian Test Symposium provides an international forum for engineers and researchers from all countries of the World, especially from Asia, to present and discuss various aspects of system, board and device testing with design, manufacturing and field considerations in mind. The official language of the symposium is English.

Topics of interest include, but are not limited to:

- ✧ Automatic Test Generation / Fault Simulation
- ✧ Synthesis for Testability / Design for Testability
- ✧ Built-In Self-Test
- ✧ On-line Testing
- ✧ Fault Modeling & Diagnosis
- ✧ Mixed-Signal Test
- ✧ Software Testing / Software Design for Test
- ✧ Network Protocol Testing
- ✧ Design Verification
- ✧ Electron-Beam Testing
- ✧ Economics of Test
- ✧ Fault Tolerance
- ✧ Delay testing / IDDQ Test
- ✧ System-on-a-Chip Test
- ✧ Microprocessor Test
- ✧ Nanochip & biochip Testing

SUBMISSIONS

Regular session: Original technical papers on the above topics are invited. Paper submissions should be complete manuscripts, not extending six pages (inclusive of figures, tables, and bibliography) in a standard IEEE two-column format. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include: author name(s) and affiliation(s), and the mailing address, phone number, fax number, and e-mail address of the contact author. A 50-words abstract and five keywords are also required. Electronic submissions (PDF or PS files) are strongly recommended. Paper submissions should be emailed to:

ats07@ict.ac.cn.

The submission will be considered evidence that upon acceptance the author(s) will prepare the final manuscript (6 pages for regular session) in time for inclusion in the proceedings and will present the paper at the Symposium.

Industry session: This session will address a wide range of practical problems in LSI test, board and system test, diagnosis, failure analysis, design verification, and so on. This session will consist of brief presentations followed by poster presentations. A one-page abstract is required for submission. Each submission should also include the complete address and designate a contact person and a presenter. Abstract submissions should be emailed to Industrial Arrangement Chair (uzzaman@cadence.com).

KEY DATES

Submission deadline: **March 25, 2007** (Regular session); **May 12, 2007** (Industry session)

Notification of acceptance: **May 31, 2007**

Camera-ready copy: **June 29, 2007**

Symposium: **October 9-11, 2007**

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